

## PATENT APPLICATION

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Jeong-Hoon AHN, et al.  
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U.S. PATENT DOCUMENTS

Exam Init	Ref	Document Number	Issue Date	Name	Class	Sub Class
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Exam Init	Ref	Document Number	Publication Date	Country	Name
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One

Lin, et al. "Single Mask Metal-Metal-Insulator-Metal (MIM) Capacitor with Copper Damascene Metallization for Sub-0.18 $\mu$ m Mixed Mode Signal and System-on-a Chip (SoC) Applications" IEEE 2000, pp.111-113 \*

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M. Armacost, et al. "A High Reliability Metal Insulator Metal Capacitor for 0.18 $\mu$ m Copper Technology" IEEE 2000, IEDM, pp.157-160 \*

\* No month cited

Examiner: Quillie

Date Considered: 2/21/06